BLF8G27LS-100V; **BLF8G27LS-100GV**

Power LDMOS transistor

Rev. 4 — 26 September 2013

Product data sheet

1. Product profile

1.1 General description

100 W LDMOS power transistor with improved video bandwidth for base station applications at frequencies from 2500 MHz to 2700 MHz.

Table 1. Typical performance

Typical RF performance at T_{case} = 25 °C in a common source class-AB production test circuit.

Test signal	f	I _{Dq}	V_{DS}	P _{L(AV)}	Gp	η_D	ACPR _{5M}
	(MHz)	(mA)	(V)	(W)	(dB)	(%)	(dBc)
2-carrier W-CDMA	2500 to 2700	900	28	25	17	28	-32 [<u>1]</u>

^[1] Test signal: 3GPP test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on CCDF per carrier; 5 MHz carrier spacing.

1.2 Features and benefits

- Excellent ruggedness
- High efficiency
- Low R_{th} providing excellent thermal stability
- Decoupling leads to enable improved video bandwidth (110 MHz typical)
- Designed for broadband operation (2500 MHz to 2700 MHz)
- Lower output capacitance for improved performance in Doherty applications
- Designed for low memory effects providing excellent pre-distortability
- Internally matched for ease of use
- Integrated ESD protection
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

RF power amplifiers for base stations and multi carrier applications in the 2500 MHz to 2700 MHz frequency range



2. Pinning information

Table 2. Pinning

3 source [1] 4 decoupling lead 5 decoupling lead 6 n.c. 7 n.c. BLF8G27LS-100GV (SOT1244C) 1 drain 2 gate 3 source [1] 4 decoupling lead 5 decoupling lead 6 n.c. 3 aaa-0036 6 aaa-0036	Table 2.	Pinning		
1 drain 2 gate 3 source [1] 4 decoupling lead 5 decoupling lead 6 n.c. 7 n.c. BLF8G27LS-100GV (SOT1244C) 1 drain 2 gate 3 source [1] 4 decoupling lead 5 decoupling lead 5 decoupling lead 6 n.c.	Pin	Description	Simplified outline	Graphic symbol
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3 source [1] 4 decoupling lead 5 decoupling lead 6 n.c. 7 n.c. BLF8G27LS-100GV (SOT1244C) 1 drain 2 gate 3 source [1] 4 decoupling lead 5 decoupling lead 6 n.c.	2	gate		6 7 → 1 → 4,5
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BLF8G27LS-100GV (SOT1244C) 1	6	n.c.		
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3 source [1] 4 decoupling lead 5 decoupling lead 6 n.c.	2	gate		6.7→1 → 4,5
5 decoupling lead 6 2 7 aaa-0036	3	source	11	2
6 n.c. 6 2 7	4	decoupling lead		3
6 n.c.	5	decoupling lead		aaa-003619
_	6	n.c.	The second secon	
7 n.c.	7	n.c.		

^[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	Packag	Package			
	Name	Description	Version		
BLF8G27LS-100V	-	earless flanged ceramic package; 6 leads	SOT1244B		
BLF8G27LS-100GV	-	earless flanged ceramic package; 6 leads	SOT1244C		

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	65	V
V_{GS}	gate-source voltage		-0.5	+13	V
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		-	225	°C

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
$R_{th(j-c)}$	thermal resistance from junction to case	T_{case} = 80 °C; P_L = 48 W	0.292	K/W

6. Characteristics

Table 6. DC characteristics

 $T_i = 25$ °C unless otherwise specified.

.,						
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 V; I_D = 1 mA$	65	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_D = 153 \text{ mA}$	1.5	1.9	2.3	V
I _{DSS}	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$	-	-	4.2	μΑ
I _{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	-	29	-	Α
I _{GSS}	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	420	nΑ
9 _{fs}	forward transconductance	$V_{DS} = 10 \text{ V}; I_{D} = 153 \text{ mA}$	-	1.27	-	S
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 5.35 \text{ A}$	-	0.1	-	Ω

Table 7. RF characteristics

Test signal: 2-carrier W-CDMA, 3GPP test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on the CCDF; f_1 = 2502.5 MHz; f_2 = 2507.5 MHz; f_3 = 2692.5 MHz; f_4 = 2697.5 MHz; RF performance at RF performance at RF performance at RF production test circuit.

•						
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Gp	power gain	$P_{L(AV)} = 25 \text{ W}$	15.8	17	-	dB
η_{D}	drain efficiency	$P_{L(AV)} = 25 \text{ W}$	25	28	-	%
RLin	input return loss	$P_{L(AV)} = 25 \text{ W}$	-	-10	-	dB
ACPR _{5M}	adjacent channel power ratio (5 MHz)	$P_{L(AV)} = 25 \text{ W}$	-	-32	-26	dBc

7. Test information

7.1 Ruggedness in class-AB operation

The BLF8G27LS-100V and BLF8G27LS-100GV are capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions: $V_{DS} = 28 \text{ V}$; $I_{Dq} = 900 \text{ mA}$; $P_{L} = 100 \text{ W}$; f = 2500 MHz.

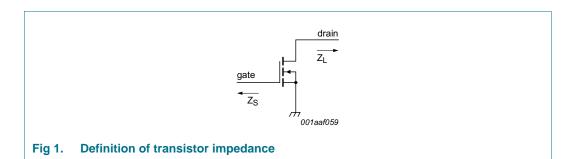
7.2 Impedance information

Table 8. Typical impedance

Measured load-pull data; $I_{Dq} = 900 \text{ mA}$; $V_{DS} = 28 \text{ V (main transistor)}$.

		-
f	Z _S [1]	Z _L [1]
(MHz)	(Ω)	(Ω)
BLF8G27LS-100V		
2500	1.2 – j4.6	2.7 – j2.7
2600	2.3 – j5.5	2.5 – j2.5
2700	3.8 – j5.2	2.1 – j2.6
BLF8G27LS-100GV		
2500	1.7 – j7.4	2.4 – j4.9
2600	2.8 – j8.0	2.2 – j5.2
2700	4.0 – j7.9	2.0 – j5.3

[1] Z_S and Z_L defined in Figure 1.



7.3 VBW in class-AB operation

The BLF8G27LS-100V and BLF8G27LS-100GV show 110 MHz (typical) video bandwidth in class-AB test circuit in 2.6 GHz band at V_{DS} = 28 V and I_{Dq} = 0.9 A.

7.4 Test circuit

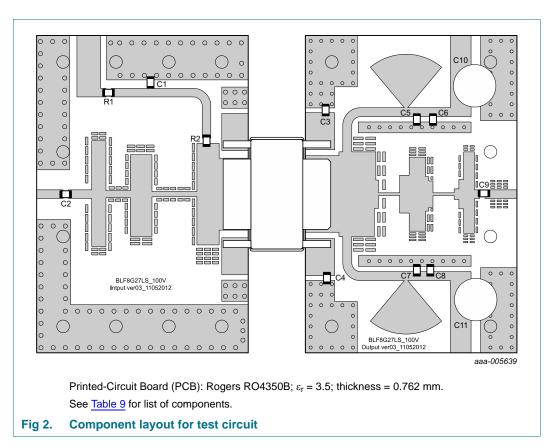


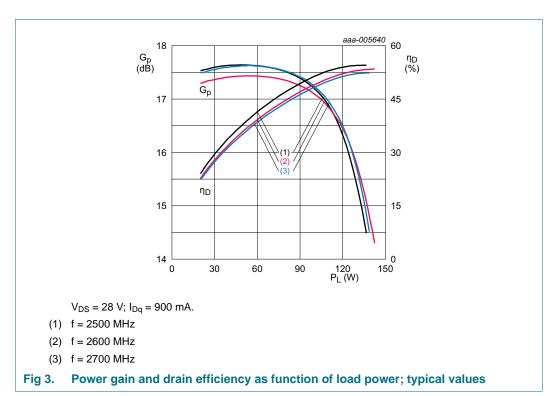
Table 9. List of components

For test circuit, see Figure 2.

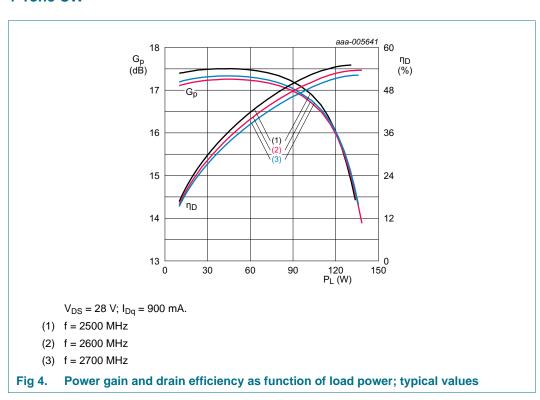
Component	Description	Value	Remarks
C1, C2, C9	multilayer ceramic chip capacitor	20 pF	ATC600F
C3, C4, C6, C8	multilayer ceramic chip capacitor	10 μF	Murata
C5, C7	multilayer ceramic chip capacitor	0.1 μF	Murata
C10, C11	electrolytic capacitor	1000 μF, 100 V	
R1, R2	chip resistor	9.1 Ω	Vishay Dale SMD 0805

7.5 Graphical data

7.5.1 Pulsed CW

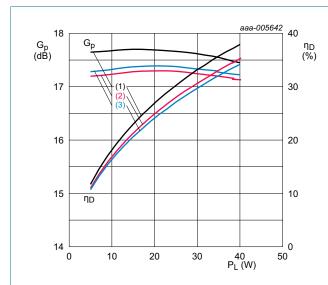


7.5.2 1-Tone CW



BLF8G27LS-100V_27LS-100GV

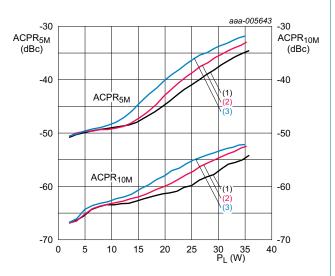
7.5.3 1-Carrier W-CDMA



 $V_{DS} = 28 \text{ V}; I_{Dq} = 900 \text{ mA}.$

- (1) f = 2500 MHz
- (2) f = 2600 MHz
- (3) f = 2700 MHz

Fig 5. Power gain and drain efficiency as function of load power; typical values

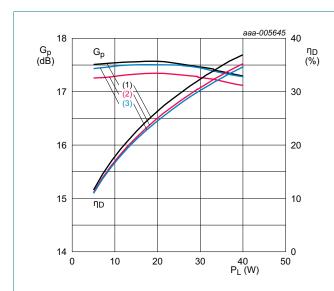


 $V_{DS} = 28 \text{ V}; I_{Dq} = 900 \text{ mA}.$

- (1) f = 2500 MHz
- (2) f = 2600 MHz
- (3) f = 2700 MHz

Fig 6. Adjacent channel power ratio (5 MHz) and Adjacent channel power ratio (10 MHz) as function of load power; typical values

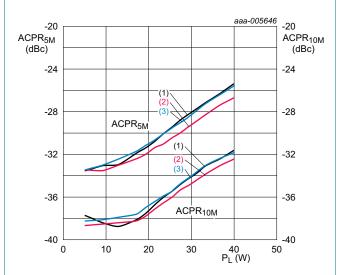
7.5.4 2-Carrier W-CDMA



 $V_{DS} = 28 \text{ V}; I_{Dq} = 900 \text{ mA}.$

- (1) f = 2500 MHz
- (2) f = 2600 MHz
- (3) f = 2700 MHz

Fig 7. Power gain and drain efficiency as function of load power; typical values

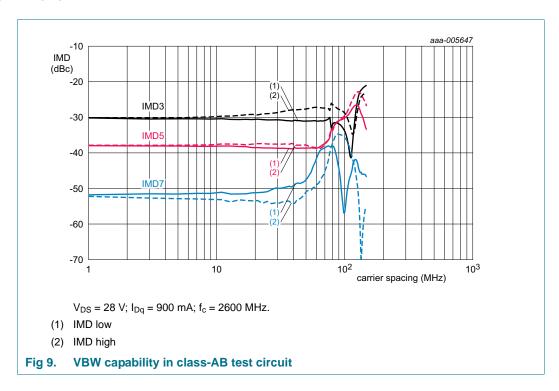


 $V_{DS} = 28 \text{ V}; I_{Dq} = 900 \text{ mA}.$

- (1) f = 2500 MHz
- (2) f = 2600 MHz
- (3) f = 2700 MHz

Fig 8. Adjacent channel power ratio (5 MHz) and Adjacent channel power ratio (10 MHz) as function of load power; typical values

7.5.5 2-Tone VBW



BLF8G27LS-100V_27LS-100GV

8. Package outline

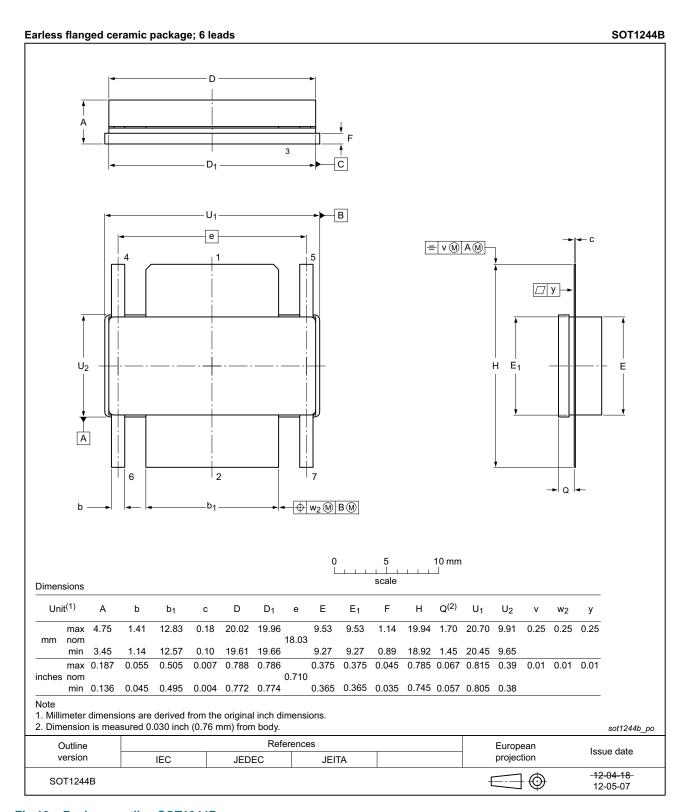


Fig 10. Package outline SOT1244B

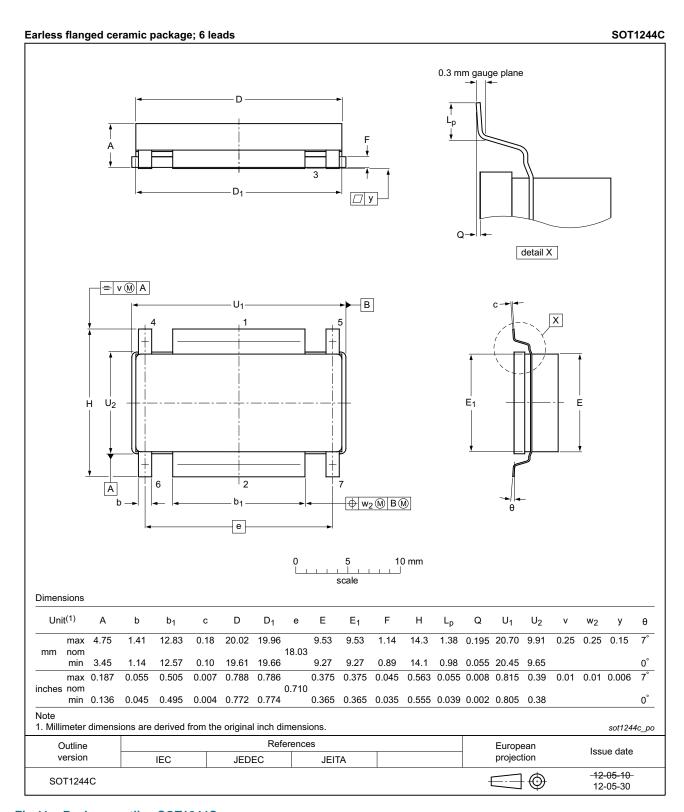


Fig 11. Package outline SOT1244C

9. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

10. Abbreviations

Table 10. Abbreviations

Acronym	Description
3GPP	Third Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
CW	Continuous Wave
DPCH	Dedicated Physical CHannel
ESD	ElectroStatic Discharge
IMD	InterModulation Distortion
LDMOS	Laterally Diffused Metal Oxide Semiconductor
PAR	Peak-to-Average Ratio
SMD	Surface Mounted Device
VBW	Video BandWidth
VSWR	Voltage Standing Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

11. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF8G27LS-100V_27LS-100GV v.4	20130926	Product data sheet	-	BLF8G27LS-100V v.3
Modifications:		sheet now describes bot _S-100GV products.	h the BLF8G27LS	-100V and the
	 Section 1.3 	2 on page 1: Section ha	s been updated.	
	 Section 7.3 	2 on page 4: Section ha	s been updated.	
BLF8G27LS-100V v.3	20130129	Product data sheet	-	BLF8G27LS-100V v.2
BLF8G27LS-100V v.2	20121203	Product data sheet	-	BLF8G27LS-100V v.1
BLF8G27LS-100V v.1	20120817	Objective data sheet	-	-

12. Legal information

12.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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BLF8G27LS-100(G)V

Power LDMOS transistor

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Power LDMOS transistor

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